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| Supplementary Table 1 *Quality Criteria* |
| **Author (year)** | **Population (country)** | **Tests** | **Illiteracy** | **Language** | **Adaptations** | **Feasibility** | **Psycho-metrics** | **Circularity** | **Sources** | **Criteria** | **Sum** |
| Aprahamian et al. (2010) | Brazil | CDT, CVF | 1 | 1 | 1 | 0 | 1 | 1 | 1 | 2 | 8 |
| Baek et al. (2012) | Korea | SVLT, KSRT | 0 | 1 | 1 | 1 | 1 | 0 | 2 | 2 | 8 |
| Baiyewu et al. (2005) | Nigeria | SDT, Constructional Praxis Test | 1 | 0 | 0 | 1 | 1 | 0 | 2 (C) | 1 | 6 |
| Caramelli et al. (2007) | Brazil | CVF | 1 | 0 | 0 | 0 | 1 | 0 | 1 | 2 | 5 |
| Chan et al. (2002) | Chinese (Hong Kong) | Olfactory Identification Test | 1 | 1 | 3 | 1 | 1 | 0 | 0 | 1 | 8 |
| Chan et al. (2005) | Chinese (Hong Kong) | CDT | 1 | 1 | 0 | 1 | 2 | 1 | 1 | 1 | 8 |
| Chang et al. (2010) | Taiwan | CVVLT | 1 | 1 | 1 | 0 | 1 | 1 | 2 | 2 | 9 |
| Chiu et al. (1997) | Chinese (Hong Kong) | CVF | 1 | 0 | 1 | 1 | 2 | 1 | 0 | 1 | 7 |
| Chung (2009) | Chinese (Hong Kong) | FOME | 1 | 0 | 0 | 1 | 2 | 1 | 0 | 0 | 5 |
| Das et al. (2007) | India | Constructional Praxis Test, CVF, Object naming test, Memory test | 1 | 1 | 1 | 0 | 2 | 0 | 1 | 2 | 8 |
| de Paula et al. (2010) | Brazil | Digit Span (WAIS-III), Corsi Blocks, CDT, CVF , Token Test | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 2 | 4 |
| de Paula et al. (2012) | Brazil | Tower of London | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 2 | 2 |
| de Paula et al. (2013a) | Brazil | CDT, SDT | 1 | 0 | 0 | 1 | 1 | 0 | 1 | 2 | 6 |
| de Paula et al. (2013b) | Brazil | Digit Span (WAIS-III), CDT, SDT, CVF, letter fluency, TN-LIN Naming\*, Token Test, RAVLT | 1 | 1 | 0-1 | 0-1 | 2 | 0 | 2 (C) | 2 | 8-9 |
| de Paula et al. (2015) | Brazil | Five Digit Test\* | 0 | 0 | 0 | 0 | 1 | 1 | 2 (C) | 2 | 6 |
| Fernandez (2013) | Argentina | Cordoba Naming Test\* | 0 | 1 | 3 | 0 | 1 | 0 | 2 (C) | 2 | 9 |
| Grober et al. (2014) | Latino (USA) | pFCSRT | 0 | 1 | 1 | 1 | 1 | 0 | 1 | 1 | 6 |
| Jacinto et al. (2014) | Brazil | Digit Span (unspecified), CDT, CVF, Naming Test (BCSB)\*, List learning (BCSB; picture based)\* | 0 | 0 | 0 | 0 | 1 | 0 | 2 (C) | 0 | 3 |
| Kim et al. (2014) | Korea | TMT Black-and-White | 1 | 0 | 1 | 1 | 1 | 0 | 0 | 2 | 6 |
| Kim et al. (2017) | Korea | BNT-Korean (CERAD) | 0 | 1 | 3 | 1 | 1 | 0 | 2 | 1 | 9 |
| Lam et al. (1998) | Chinese (Hong Kong) | CDT | 0 | 1 | 0 | 1 | 2 | 1 | 0 | 1 | 6 |
| Lee et al. (2002) | Korea | CERAD battery | 1 | 1 | 3 | 1 | 2 | 0 | 0 | 2 | 10 |
| Loewenstein et al. (1993) | Cuban American (USA) | Digit Span (WAIS-R), Block Design, Object Assembly (WAIS-R), letter fluency, BNT, Comprehension (WAIS-R), WMS-LM, WMS-VR | 0 | 1 | 3 | 0 | 0 | 0 | 1 | 2 | 7 |
| Loewenstein et al. (1995) | Hispanics (USA) | FOME | 0 | 1 | 0 | 1 | 1 | 0 | 2 | 2 | 7 |
| Maillet et al. (2016) | Mixed (France) | TNI-93\* | 1 | 0 | 3 | 0 | 1 | 1 | 0 | 1 | 7 |
| Maillet et al. (2017) | Mixed (France) | TMA-93\* | 1 | 1 | 3 | 1 | 1 | 1 | 0 | 1 | 9 |
| Marquez de la Plata et al. (2008) | Hispanics (USA) | MBNT-S, TNT, 15-item Spanish Naming Test | 0 | 1 | 1 | 0 | 2 | 0 | 0 | 1 | 5 |
| Marquez de la Plata et al. (2009) | Colombia | BNT (CERAD), MBNT-S, TNT | 0 | 1 | 1 | 0 | 2 | 0 | 0 | 1 | 5 |
| Mok et al. (2004) | Chinese (Hong Kong) | CVF | 1 | 1 | 0 | 1 | 1 | 0 | 0 | 2 | 6 |
| Nielsen et al. (2018) | Mixed (Western Europe) | CNTB | 1 | 1 | 0 | 1 | 1 | 0 | 2 (C) | 2 | 8 |
| Park et al. (2018) | Korea | CC-SIT | 0 | 0 | 0 | 0 | 1 | 0 | 0 (C) | 2 | 3 |
| Qiao et al. (2016) | China | Digit Span (WAIS-R), Block Design (WISC-III), FOME | 1 | 1 | 0 | 0 | 1 | 0 | 1 | 0 | 4 |
| Radanovic et al. (2007) | Brazil | CVF, BNT (CERAD), Naming Test (BCSB)\* | 1 | 1 | 0 | 1 | 1 | 0 | 1 | 2 | 7 |
| Rideaux et al. (2012) | Latino (USA) | FOME | 0 | 1 | 1 | 0 | 1 | 0 | 1 (C) | 1 | 5 |
| Sahadevan et al. (2002) | Chinese (Singapore) | Constructional Praxis Test, Block Design, Object Assembly (WAIS-R), CVF, BNT, Word list memory | 1 | 1 | 1 | 0-1 | 1 | 1 | 2 | 2 | 9-10 |
| Saka et al. (2006) | Turkey | Enhanced Cued Recall | 1 | 1 | 1 | 1 | 1 | 1 | 2 | 2 | 10 |
| Salmon et al. (1995) | China | Digit Span (WAIS-R), TMT, Digit Symbol Substitution (WAIS-R), CDT, Block Design (WAIS-R), CVF, BNT, Vocabulary (WAIS-R), FOME | 1 | 1 | 0-1 | 0-1 | 0-1 | 0 | 0 | 0 | 3-5 |
| Shim et al. (2015) | Korea | LICA | 1 | 1 | 3 | 0 | 2 | 0 | 2 | 2 | 11 |
| Storey et al. (2002) | Mixed NESB (Australia) | CDT | 0 | 1 | 0 | 0 | 2 | 1 | 0 | 1 | 5 |
| Takada et al. (2006) | Brazil | List learning (CERAD), List learning (BCSB; picture based)\* | 1 | 1 | 0 | 0 | 1 | 0 | 1 (C) | 2 | 6 |
| Unverzagt et al. (1999) | Jamaica | CERAD battery | 0 | 1 | 1 | 1 | 1 | 1 | 0 (C) | 1 | 6 |
| Verghese et al. (2012) | India | PMIS\* | 1 | 1 | 3 | 1 | 1 | 1 | 1 (C) | 1 | 10 |
| Wu et al. (2017) | China | NLCA | 0 | 1 | 1 | 1 | 2 | 0 | 0 | 2 | 7 |
| Yap et al. (2007) | Chinese (Singapore) | CDT | 1 | 1 | 0 | 1 | 1 | 1 | 2 (C) | 2 | 9 |
| CDT = Clock Drawing Test; CVF = category verbal fluency; SVLT = Seoul Verbal Learning Test; KSRT = Korean Story Recall Test; SDT = Stick Design Test; CVVLT = Chinese Version Verbal Learning Test; FOME = Fuld Object Memory Evaluation; TN-LIN = The Neuropsychological Investigations Laboratory Naming Test; RAVLT = Rey Auditory Verbal Learning Test; pFCSRT = Free and Cued Selective Reminding Test (picture version); BCSB = Brief Cognitive Screening Battery; TMT = Trail Making Test; BNT = Boston Naming Test; CERAD = Consortium to Establish a Registry for Alzheimer’s Disease; WAIS-R = Wechsler Adult Intelligence Scale-Revised; WMS-LM = Wechsler Memory Scale Logical Memory (original); WMS-VR = Wechsler Memory Scale Visual Reproduction (original); TNI-93 = Test des Neuf Images du 93; TMA-93 = Memory Associative Test of the district of Seine-Saint-Denis; MBNT-S = Modified Boston Naming Test Spanish; TNT = Texas Spanish Naming Test; CNTB = European Cross-Cultural Neuropsychological Test Battery; CC-SIT = Cross-Cultural Smell Identification Test; WISC-III = Wechsler Intelligence Scale for Children-III; LICA = Literacy Independent Cognitive Assessment; PMIS = Picture Based Memory Impairment Screen; NLCA = Non-Language Based Cognitive Assessment\* Assembled test |